

NFP E and H Field Probe Set

Accurate and Repeatable High-Resolution EMC and EMI diagnostic with Handheld Near Field Probes on your lab-bench



Y.I.C. Technologies set of EM probes kit designed for measuring near field radiated emissions for EMC/EMI pre-compliance testing.

The probes can be used to locate, identify, measure and characterize potential sources of electromagnetic radiation and interference radiated from traces or components of electronic PCBs, assemblies or products. The probe output is proportional to the magnetic field (H) strength present at the probe location.

A compatible Spectrum Analyzer with 50 Ω input is required and the probes can be used as handheld standalone probes or mounted on Y.I.C. Technologies EMProbe robotic arm for high resolution scans.



Key features

- Fully integrated with Y.I.C. Technologies EMViewer and EMProbe
- Normalization and correction when using the EMViewer software
- Flat response within the range of operation
- Slim Design and Protective Coating
- 18GHz Measured Cable included

Applications

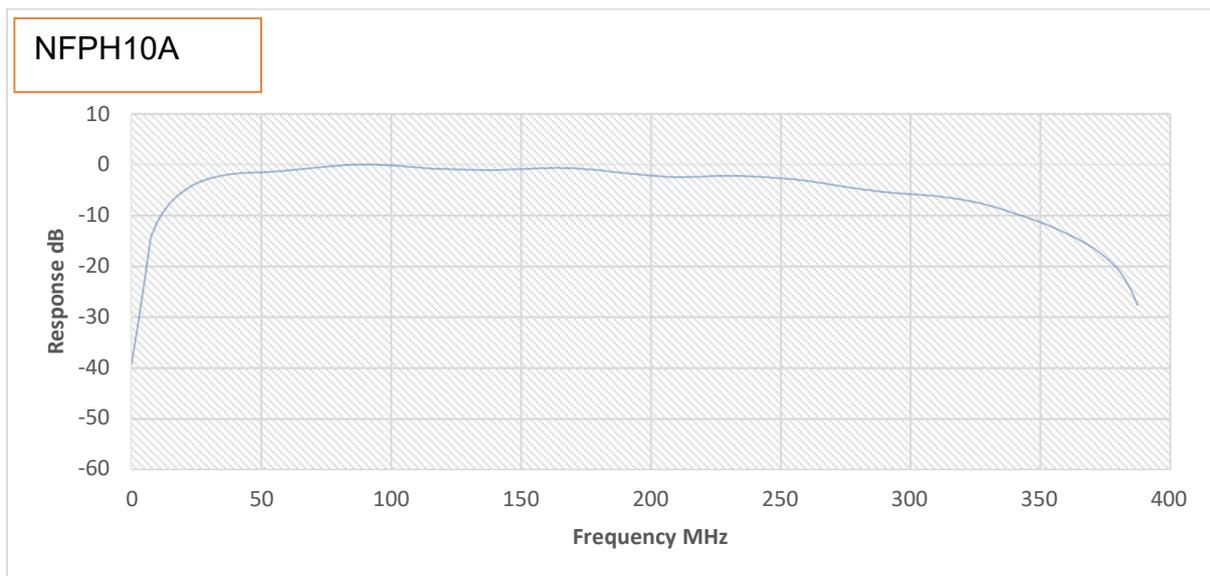
EMC/EMI Pre-Compliance Magnetic Near-Field Measurements

- Magnetic Near Field mapping
- Magnetic Immunity Testing

Features

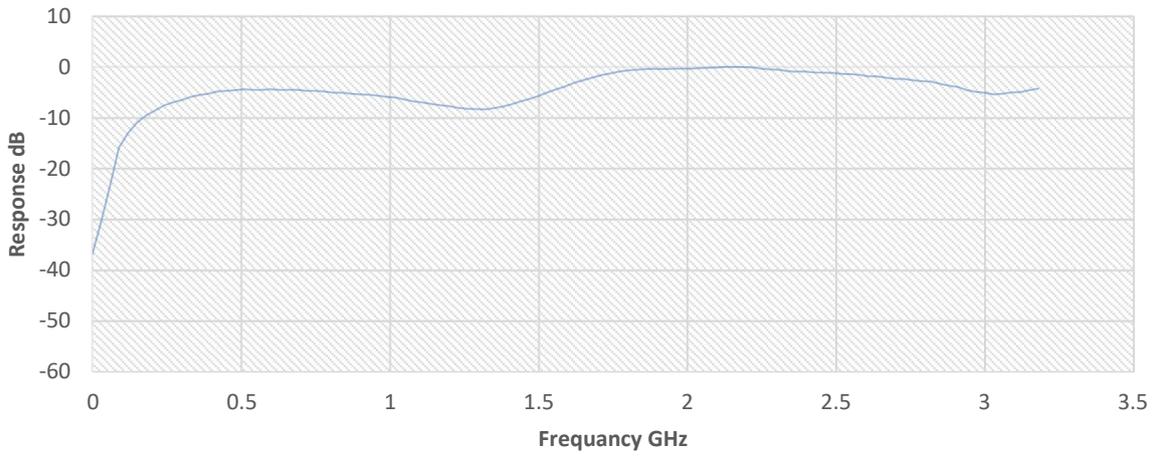
| Model | NFPE10A | NFPH10A | NFPH20A | NFPH30A |
|-----------------|---------|--------------|---------------|------------|
| Frequency Range | TBD | 10MHz-330MHz | 155MHz-3.1GHz | 6GHz-16GHz |
| Marker ID | ID00 | ID10 | ID20 | ID30 |

Output and Frequency Response:

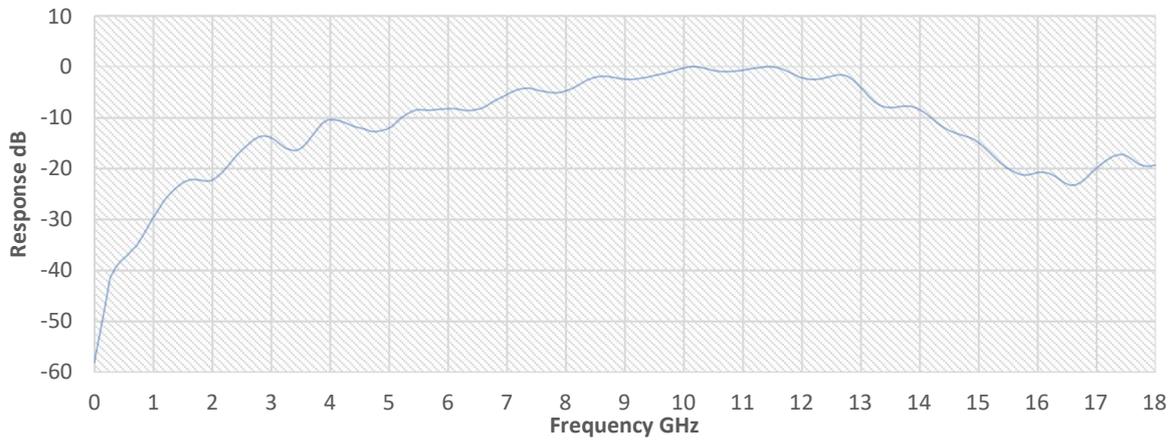




NFPH20A



NFPH30A



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